# 

#### PRELIMINARY

## ICS889872

#### DIFFERENTIAL-TO-LVDS BUFFER/DIVIDER W/INTERNAL TERMINATION

## **General Description**



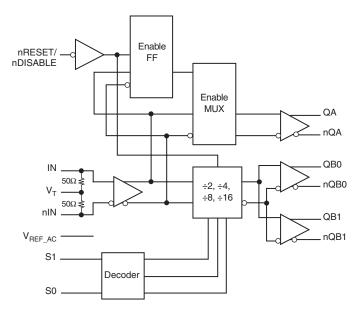
The ICS889872 is a high speed Differential-to-LVDS Buffer/Divider w/Internal Termination and is a member of the HiPerClockS<sup>™</sup>family of high performance clock solutions from IDT. The ICS889872 has a selectable ÷2, ÷4, ÷8, ÷16 output

dividers. The clock input has internal termination resistors, allowing it to interface with several differential signal types while minimizing the number of required external components. The device is packaged in a small, 3mm x 3mm VFQFN package, making it ideal for use on space-constrained boards.

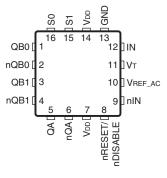
## **Features**

- Three LVDS outputs
- Frequency divide select options: ÷4, ÷6: >2GHz, ÷8, ÷16: >1.6GHz
- IN, nIN input can accept the following differential input levels: LVPECL, LVDS, CML
- Output frequency: >2GHz
- Cycle-to-cycle jitter: 1ps (typical)
- Total jitter: 10ps (typical)
- Output skew: 7ps (typical), QA/nQA outputs
- Part-to-part skew: 250ps (typical)
- Propagation Delay: 750ps (typical), QA/nQA outputs
- Full 2.5V supply mode
- -40°C to 85°C ambient operating temperature
- Available in both standard (RoHS 5) and lead-free (RoHS 6) packages

## **Block Diagram**



## Pin Assignment



#### ICS889872

16-Lead VFQFN 3mm x 3mm x 0.95mm package body K Package Top View

The Preliminary Information presented herein represents a product in pre-production. The noted characteristics are based on initial product characterization and/or qualification. Integrated Device Technology, Incorporated (IDT) reserves the right to change any circuitry or specifications without notice.

## **Table 1. Pin Descriptions**

Number	Name	Т	уре	Description
1, 2	QB0, nQB0	Output		Differential output pair. Divide by 2, 4, 8, 16. Unused outputs must be terminated with 100W across the pin (QB0/nQB0). LVDS interface levels.
3, 4	QB1, nQB1	Output		Differential output pair. Divide by 2, 4, 8, 16. Unused outputs must be terminated with 100W across the pin (QB1nQB1). LVDS interface levels.
5, 6	QA, nQA	Output		Differential undivided output pair. LVDS interface levels.
7, 14	V <sub>DD</sub>	Power		Power supply pins.
8	nRESET/ nDISABLE	Input	Pullup	Output reset and enable/disable pin. When LOW, resets the divider select, and align Bank A and Bank B edges. In addition, when LOW, Bank A and Bank B will be disabled. Input threshold is $V_{DD}/2V$ . Includes a $37k\Omega$ pullup resistor. LVTTL / LVCMOS interface levels.
9	nIN	Input		Inverting differential LVPECL clock input. RT = $50\Omega$ termination to V <sub>T</sub> .
10	V <sub>REF_AC</sub>	Output		Reference voltage for AC-coupled applications. Equal to V <sub>DD</sub> – 1.4V (approx.). Maximum sink/source current is 0.5mA.
11	V <sub>T</sub>	Input		Termination input. Leave pin floating.
12	IN	Input		Non-inverting LVPECL differential clock input. RT = $50\Omega$ termination to V <sub>T</sub> .
13	GND	Power		Power supply ground.
15, 16	S1, S0	Input	Pullup	Select pins. Logic HIGH if left unconnected (÷16 mode). S0 = LSB. Input threshold is VDD/2. 37kW pullup resistor. LVCMOS/LVTTL interface levels.

NOTE: Pullup refers to internal input resistors. See Table 2, Pin Characteristics, for typical values.

## **Table 2. Pin Characteristics**

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
R <sub>PULLUP</sub>	Input Pullup Resistor			37		kΩ

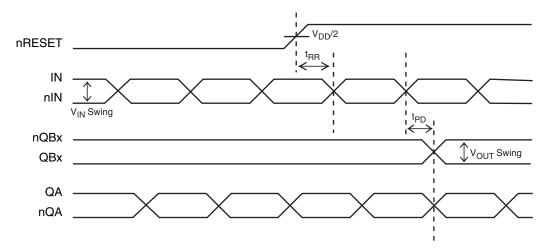
## **Function Tables**

#### Table 3A. Control Input Function Table

Input	Outputs				
nRESET	QA, QBx	nQA, nQBx			
0	Disabled; LOW	Disabled; HIGH			
1	Enabled	Enabled			

NOTE: After nRESET switches, the clock outputs are disabled or enabled following a falling input clock edge as shown in *Figure 1*.

#### Figure 1. nRESET Timing Diagram



#### Table 3B. Truth Table

Input	s		Outputs		
nRESET/nDISABLE	S1	S0	Bank A	Bank B	
1	0	0	Input Clock	Input Clock ÷2	
1	0	1	Input Clock	Input Clock ÷4	
1	1	0	Input Clock	Input Clock ÷8	
1	1	1	Input Clock	Input Clock ÷16	
0	Х	Х	QA = LOW, nQA = HIGH; NOTE 1	QBx = LOW, nQBx = HIGH; NOTE 2	

NOTE 1: On the next negative transition of the input signal.

NOTE 2: Asynchronous reset/disable function. Absolute Maximum Ratings

## **Absolute Maximum Ratings**

NOTE: Stresses beyond those listed under *Absolute Maximum Ratings* may cause permanent damage to the device. These ratings are stress specifications only. Functional operation of product at these conditions or any conditions beyond those listed in the *DC Characteristics or AC Characteristics* is not implied. Exposure to absolute maximum rating conditions for extended periods may affect product reliability.

Item	Rating
Supply Voltage, V <sub>DD</sub>	4.6V
Inputs, V <sub>I</sub>	-0.5V to V <sub>DD</sub> + 0.5V
Outputs, I <sub>O</sub> Continuos Current Surge Current	10mA 15mA
Input Current, IN, nIN	±50mA
V <sub>T</sub> Current, I <sub>VT</sub>	±100mA
Input Sink/Source, I <sub>REF_AC</sub>	± 0.5mA
Operating Temperature Range, T <sub>A</sub>	-40°C to +85°C
Package Thermal Impedance, $\theta_{JA}$ , (Junction-to-Ambient)	51.5°C/W (0 lfpm)
Storage Temperature, T <sub>STG</sub>	-65°C to 150°C

## **DC Electrical Characteristics**

Table 4A. Power Supply DC Characteristics,  $V_{DD} = 2.5V \pm 5\%$ ,  $T_A = -40^{\circ}C$  to  $85^{\circ}C$ 

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V <sub>DD</sub>	Positive Supply Voltage		2.375	2.5	2.625	V
I <sub>DD</sub>	Power Supply Current			80		mA

#### Table 4B. LVCMOS/LVTTL DC Characteristics, $V_{DD} = 2.5V \pm 5\%$ , $T_A = -40^{\circ}C$ to $85^{\circ}C$

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V <sub>IH</sub>	Input High Voltage		2		V <sub>DD</sub> + 0.3	V
V <sub>IL</sub>	Input Low Voltage		0		0.8	V
I <sub>IH</sub>	Input High Current	$V_{DD} = V_{IN} = 2.625V$			5	μA
I <sub>IL</sub>	Input Low Current	V <sub>DD</sub> = 2.625V, V <sub>IN</sub> = 0V	-150			μA

Symbol	Parameter		Test Conditions	Minimum	Typical	Maximum	Units
R <sub>IN</sub>	Differential Input Resistance	(IN, nIN)			100		Ω
V <sub>IH</sub>	Input High Voltage	(IN, nIN)		1.2		V <sub>DD</sub>	V
V <sub>IL</sub>	Input Low Voltage	(IN, nIN)		0		V <sub>DD</sub> – 0.15	V
V <sub>IN</sub>	Input Voltage Swing			0.15		2.8	V
$V_{\text{DIFF}_{\text{IN}}}$	Differential Input Voltage Swin	g		0.3			V
I <sub>IN</sub>	Input Current	(IN, nIN)				45	mA
V <sub>REF_AC</sub>	Bias Voltage				V <sub>DD</sub> – 1.35		V

#### Table 4C. Differential DC Characteristics, $V_{DD} = 2.5V \pm 5\%$ , $T_A = -40^{\circ}C$ to $85^{\circ}C$

Table 4D. LVDS DC Characteristics,  $V_{DD}$  = 2.5V ± 5%,  $T_A$  = -40°C to 85°C

Symbol	Parameter	Test Conditions	Minimum	Typical	Maximum	Units
V <sub>OUT</sub>	Output Voltage Swing			350		mV
V <sub>OH</sub>	Output High Voltage			1.475		V
V <sub>OL</sub>	Output Low Voltage		0.925			V
V <sub>CCM</sub>	Output Common Mode Voltage			1.35		V
$\Delta V_{OCM}$	Change in Common Mode Voltage				50	mV

## **AC Electrical Characteristics**

#### Table 5. AC Characteristics, $V_{DD} = 2.5V \pm 5\%$ , $T_A = -40^{\circ}C$ to $85^{\circ}C$

Parameter	Symbol		Test Conditions	Minimum	Typical	Maximum	Units
f	Output Frequency		÷2, ÷4		>2		GHz
f <sub>MAX</sub>	Input Frequency		÷8, ÷16		>1.6		GHz
+	Propagation Delay;	IN-to-Q	Input Swing: <400mV		750		ps
t <sub>PD</sub>	NOTE 1, 2	IN-10-Q	Input Swing: ≥400mV		750		ps
tel(a)	Output Skew; NOTE 2, 3, 4	QB0-to-QB1			7		ps
<i>t</i> sk(o)		QA-to-QB			60		ps
<i>t</i> sk(pp)	Part-to-Part Skew; NO	DTE 2, 4, 5			250		ps
<i>t</i> jit(cc)	Cycle-to-Cycle Jitter; N	NOTE 2, 6			1		ps
<i>t</i> jit(j)	Total Jitter; NOTE 2				10		ps
t <sub>RR</sub>	Reset Recovery Time; NOTE 2			600			ps
t <sub>R</sub> / t <sub>F</sub>	Output Rise/Fall Time;	; NOTE 2			150		ps

All parameters characterized at  $\leq$  1GHz unless otherwise noted.

NOTE 1: Measured from the differential input crossing point to the differential output crossing point.

NOTE 2: Specs are design targets.

NOTE 3: Defined as skew between outputs at the same supply voltage and with equal load conditions.

Measured at the output differential cross points.

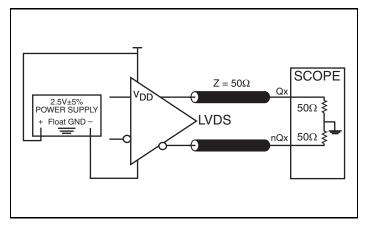
NOTE 4: This parameter is defined in accordance with JEDEC Standard 65.

NOTE 5: Defined as skew between outputs on different devices operating at the same supply voltages and with equal load conditions. Using the same type of inputs on each device, the outputs are measured at the differential cross points.

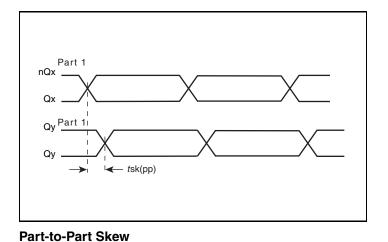
NOTE 6: The cycle-to-cycle jitter on the input will equal the jitter on the output. The part does not add jitter.

5

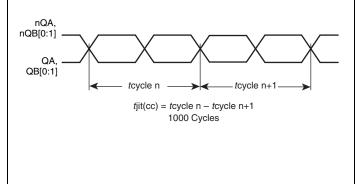
## **Parameter Measurement Information**



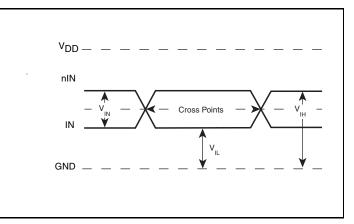
LVDS Output Load AC Test Circuit



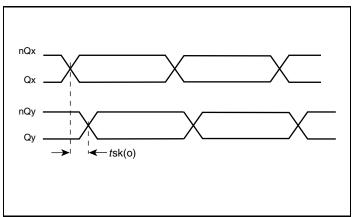
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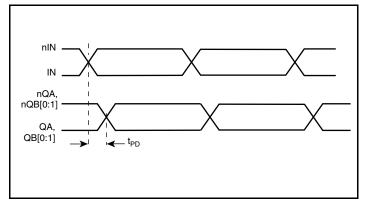
**Cycle-to-Cycle Jitter** 



#### **Differential Input Level**

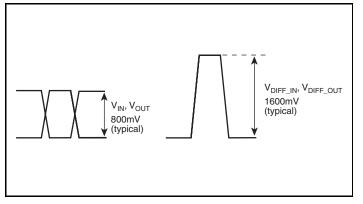


**Output Skew** 

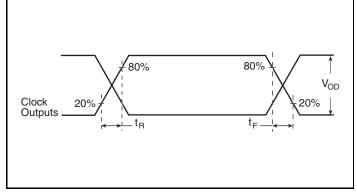


#### **Propagation Delay**

## Parameter Measurement Information, continued



Single-Ended & Differential Input Voltage Swing



#### **Output Rise/Fall Time**

## **Application Information**

## Wiring the Differential Input to Accept Single Ended Levels

*Figure 2* shows how the differential input can be wired to accept single ended levels. The reference voltage V\_REF =  $V_{DD}/2$  is generated by the bias resistors R1, R2 and C1. This bias circuit should be located as close as possible to the input pin. The ratio of R1 and R2 might need to be adjusted to position the V\_REF in the center of the input voltage swing. For example, if the input clock swing is only 2.5V and V<sub>DD</sub> = 3.3V, V\_REF should be 1.25V and R2/R1 = 0.609.

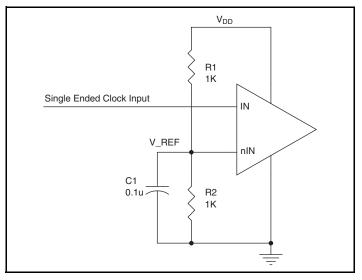


Figure 2. Single-Ended Signal Driving Differential Input

### Differential Input with Built-in 50 $\Omega$ Termination Interface

The IN /nIN with built-in 50 $\Omega$  terminations accepts LVDS, LVPECL, LVHSTL, CML, SSTL and other differential signals. Both signals must meet the V<sub>PP</sub> and V<sub>CMR</sub> input requirements. *Figures 3A to 3E* show interface examples for the HiPerClockS IN/nIN input with built-in 50 $\Omega$  terminations driven by the most common driver types.

Figure 3A. HiPerClockS IN/nIN Input with Built-In 50 $\Omega$  Driven by an LVDS Driver

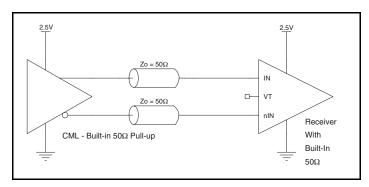


Figure 3C. HiPerClockS IN/nIN Input with Built-In 50  $\Omega$  Driven by a CML Driver with Built-In 50  $\Omega$  Pullup

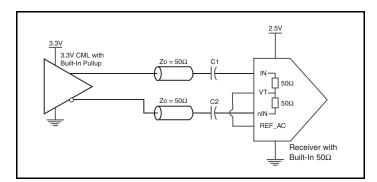


Figure 3E. HiPerClockS IN/nIN Input with Built-In 50Ω Driven by a 3.3V CML Driver with Built-In Pullup

2.5V 2.5V 2.5V VT VT VT Receiver With Built-In

The input interfaces suggested here are examples only. If the driver

Please consult with the vendor of the driver component to confirm

is from another vendor, use their termination recommendation.

the driver termination requirements.

Figure 3B. HiPerClockS IN/nIN Input with Built-In 50 $\Omega$  Driven by an LVPECL Driver

18

50Ω

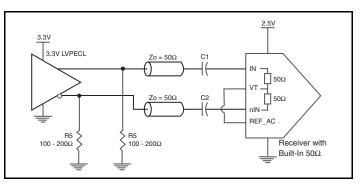


Figure 3D. HiPerClockS IN/nIN Input with Built-In 50 $\Omega$  Driven by an SSTL Driver

#### **Recommendations for Unused Input Pins**

#### Inputs:

#### **LVCMOS Select Pins**

All control pins have internal pull-ups or pull-downs; additional resistance is not required but can be added for additional protection. A  $1k\Omega$  resistor can be used.

#### **EPAD Thermal Release Path**

The EPAD provides heat transfer from the device to the P.C. board. The exposed metal pad on the PCB is connected to the ground plane through thermal vias. To guarantee the device's electrical and thermal performance, EPAD must be soldered to the exposed

#### **OUTputs:**

#### LVDS Outputs

All unused LVDS output pairs can be either left floating or terminated with  $100\Omega$  across. If they are left floating, we recommend that there is no trace attached.

metal pad on the PCB, as shown in Figure 4. For further information, please refer to the Application Note on Surface Mount Assembly of Amkor's Thermally /Electrically Enhance Leadframe Base Package, Amkor Technology.

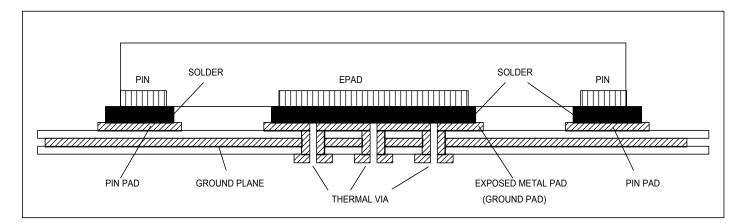


Figure 4. P.C. Board for Exposed Pad Thermal Release Path Example

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## 2.5V LVDS Driver Termination

*Figure 5* shows a typical termination for LVDS driver in characteristic impedance of  $100\Omega$  differential ( $50\Omega$  single)

transmission line environment. For buffer with multiple LDVS driver, it is recommended to terminate the unused outputs.

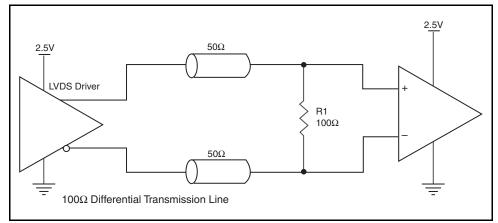


Figure 5. Typical LVDS Driver Termination

## **Power Considerations**

This section provides information on power dissipation and junction temperature for the ICS889872. Equations and example calculations are also provided.

#### 1. Power Dissipation.

The total power dissipation for the ICS889872 is the sum of the core power plus the power dissipated in the load(s). The following is the power dissipation for  $V_{DD} = 2.5V + 5\% = 2.625V$ , which gives worst case results.

Power\_MAX = V<sub>DD MAX</sub> \* I<sub>DD MAX</sub> = 2.625V \* 80mA = **210mW** 

#### 2. Junction Temperature.

Junction temperature, Tj, is the temperature at the junction of the bond wire and bond pad and directly affects the reliability of the device. The maximum recommended junction temperature for HiPerClockS devices is 125°C.

The equation for Tj is as follows: Tj =  $\theta_{JA}$  \* Pd\_total + T<sub>A</sub>

Tj = Junction Temperature

 $\theta_{JA}$  = Junction-to-Ambient Thermal Resistance

Pd\_total = Total Device Power Dissipation (example calculation is in section 1 above)

T<sub>A</sub> = Ambient Temperature

In order to calculate junction temperature, the appropriate junction-to-ambient thermal resistance  $\theta_{JA}$  must be used. Assuming no air flow and a multi-layer board, the appropriate value is 51.5°C/W per Table 6 below.

Therefore, Tj for an ambient temperature of 85°C with all outputs switching is:

 $85^{\circ}C + 0.210W * 51.5^{\circ}C/W = 95.8^{\circ}C$ . This is well below the limit of  $125^{\circ}C$ .

This calculation is only an example. Tj will obviously vary depending on the number of loaded outputs, supply voltage, air flow and the type of board (single layer or multi-layer).

#### Table 6. Thermal Resistance $\theta_{JA}$ for 16 Lead VFQFN, Forced Convection

θ <sub>JA</sub> by Velocity					
Linear Feet per Minute	0				
Multi-Layer PCB, JEDEC Standard Test Boards	51.5°C/W				

## **Reliability Information**

#### Table 7. $\theta_{\text{JA}}$ vs. Air Flow Table for a 16 Lead VFQFN

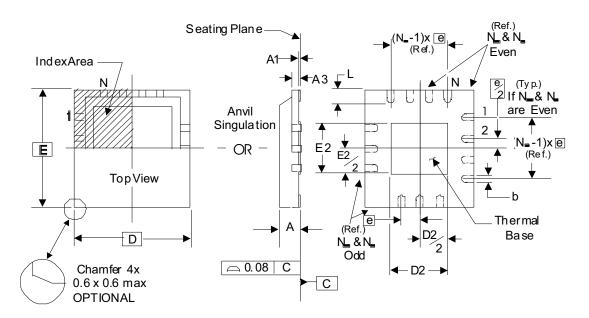
$\theta_{JA}$ by Velocity					
Linear Feet per Minute	0				
Multi-Layer PCB, JEDEC Standard Test Boards	51.5°C/W				

#### **Transistor Count**

The transistor count for ICS889872 is: 323 Pin compatible with SY89872U

## **Package Outline and Package Dimensions**

#### Package Outline - K Suffix for 16 Lead VFQFN



#### **Table 8. Package Dimensions**

JEDEC Variation: VEED-2/-4 All Dimensions in Millimeters					
Symbol	Minimum	Maximum			
N	16				
Α	0.80	1.00			
A1	0	0.05			
A3	0.25 Ref.				
b	0.18	0.30			
N <sub>D</sub> & N <sub>E</sub>	4				
D&E	3.00 Basic				
D2 & E2	1.00	1.80			
е	0.50 Basic				
L	0.30	0.50			

Reference Document: JEDEC Publication 95, MO-220

## **Ordering Information**

#### **Table 9. Ordering Information**

Part/Order Number	Marking	Package	Shipping Packaging	Temperature
ICS889872AK	872A	16 Lead VFQFN	Tube	-40°C to 85°C
ICS889872AKT	872A	16 Lead VFQFN	2500 Tape & Reel	-40°C to 85°C
ICS889872AKLF	TBD	"Lead-Free" 16 Lead VFQFN	Tube	-40°C to 85°C
ICS889872AKLFT	TBD	"Lead-Free" 16 Lead VFQFN	2500 Tape & Reel	-40°C to 85°C

NOTE: Parts that are ordered with an "LF" suffix to the part number are the Pb-Free configuration and are RoHS compliant.

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